



Application/Control No.	Applicant(s)/Patent under Reexamination	
09/974,885	LEE, JEN-FU	
Examiner	Art Unit	_
Linda Krisciunas	3623	

	SEARCHED				
Class	Subclass	Date	Examiner		
705	7	2/28/2006	LMK		
			·		
			•		

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
	-		

DATE	EXMR
1	
2/28/2006	LMK
2/28/2006	LMK
3/1/2006	LMK